

Nome da disciplina: **Métodos Cristalográficos Aplicados a Compostos Policristalinos**

Nº de créditos: **12** Carga horária: **180 horas**

Docente responsável: **Prof. Dr. Carlos de Oliveira Paiva Santos**

Docente colaborador: **não há**

### **EMENTA**

Métodos de mínimos-quadrados aplicado ao método de Rietveld, Estratégias de coleta de dados, determinação e refinamento de estruturas cristalinas com dados de difração por policristais. Análise quantitativa de fases. Determinação de tamanho de cristalito e microdeformação. Indetificação de polimorfos.

### **BIBLIOGRAFIA**

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